


<b>Search Notes</b> 	<b>Application/Control No.</b> 10731417	<b>Applicant(s)/Patent Under Reexamination</b> SINHA, AMIT
	<b>Examiner</b> Flores, Leon	<b>Art Unit</b> 2611

SEARCHED			
Class	Subclass	Date	Examiner
375	322, 326, 316	2/7/2007	LF
329	345, 346	2/7/2007	LF

SEARCH NOTES			
Search Notes		Date	Examiner
Consulted with SPE David Payne in regards to the patentability of the claims.		2/12/2007	LF
Consulted with SPE Chieh Fan in regards to claim 7.		2/7/2007	LF
Searched using NPL database (IEEE)		2/6/2007	LF
Checked for possible Double Patenting.		2/6/2007	LF

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner